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Ph.D., 36 months Full-time No experience required MS/MSc, MA Electronic components

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Mission

The objective of this thesis is to demonstrate the possibility of observing logic states in active structures of microelectronic devices using Atomic Force Microscopy (AFM).

In the long run, this technique will allow to reveal malfunctions of microelectronic circuitry at the transistor level in order to locate failure areas.

The technique could also be used to evaluate the level of risk of leakage of sensitive information stored or manipulated in microelectronic components such as encryption key or microcode.

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For more Information about the topics and the co-financial partner (found by the lab !); **contact Directeur de thèse - christina.villeneuve@laplace.univ-tlse.fr**

Then, prepare a resume, a recent transcript and a reference letter from your M2 supervisor/ engineering school director and you will be ready to apply online before March 15th, 2024 Midnight Paris time !

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Message from PhD team

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